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Barbara Haggerty

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Barbara Haggerty

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Of: Roman Frick

Filed: June 25, 2003

For: Stand For A Surgical Microscope

the specification of which is being transmitted herewith.

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Pursuant to 37 CFR 1.56

Applicant wishes to make of record the following references under the provisions of 37 C.F.R. §1.97 (legible copies are provided).

References cited

- 1) German Patent No. De 101 23 166 A1

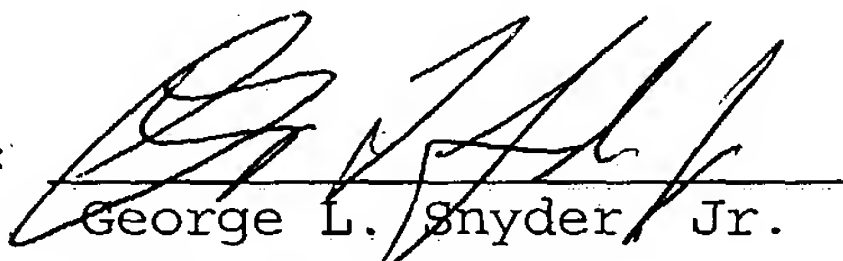
IDS For: Stand For A Surgical Microscope
Inventor: Roman Frick

Please see attached Form 1449 for list of publications.
Legible copies of all publications listed are enclosed.

The person making this statement is the patent attorney who signs below on the basis of the information supplied by the inventors, and as the attorney associated with the filing and prosecution of this application (37 CFR 1.56(a)).

Respectfully Submitted,

By:


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June 25, 2003

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet	3	of	3	Application Number	
				Filing Date	06/25/03
				First Named Inventor	Roman Frick
				Art Unit	
				Examiner Name	
				Attorney Docket Number	33997.0086

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
		US-			
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ Number ⁴ Kind Code ⁵ (if known)				
	1	DE 102 23 166 A1	12-12-2002	Leica Microsystems AG		

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.